

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/761,190 | Applicant(s)/Patent Under Reexamination KIM, KUN-TAE | |
| | Examiner JASON K. LIN | Art Unit 2425 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-2003/0131360 | 07-2003 | Joung et al. | 725/118 |
| * | B | US-6,847,406 | 01-2005 | Dantwala et al. | 348/452 |
| * | C | US-6,839,851 | 01-2005 | Saitoh et al. | 726/13 |
| * | D | US-6,704,060 | 03-2004 | Levandowski, Mark C. | 348/725 |
| * | E | US-2001/0021998 | 09-2001 | Margulis, Neal | 725/81 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.